Se	arch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/002,722	CHEN ET AL.
Examiner	Art Unit
Ted M. Wang	2611

	SEARCHED				
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report	10/26/2007	TW
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